

Features

- High speed
 12 ns
- Output enable (OE) feature (7C195 and 7C196)
- CMOS for optimum speed/power
- Low active power
 - —880 mW
- · Low standby power

—220 mW

- TTL-compatible inputs and outputs
- Automatic power-down when deselected

Functional Description

The CY7C194, CY7C195, and CY7C196 are high-performance CMOS static RAMs organized as 65,536 by 4 bits. Easy memory expansion is provided by active LOW Chip En-

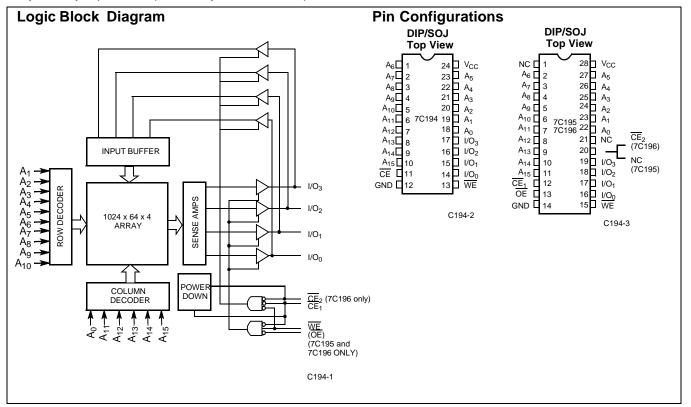
64K x 4 Static RAM

able(s) ($\overline{\text{CE}}$ on the CY7C194 and CY7C195, $\overline{\text{CE}}_1$, $\overline{\text{CE}}_2$ on the CY7C196) and three-state drivers. They have an automatic power-down feature, reducing the power consumption by 75% when deselected.

<u>Writing to the device is accomplished when the Chip Enable(s)</u> (CE on the CY7C194 and CY7C195, CE₁, CE₂ on the CY7C196) and Write Enable (WE) inputs are both LOW. Data on the four input pins (I/O₀ through I/O₃) is written into the memory location, specified on the address pins (A₀ through A₁₅).

Reading the device is accomplished by taking the Chip Enable(s) (CE on the CY7C194 and CY7C195, CE₁, CE₂ on the CY7C196) LOW, while Write Enable (WE) remains HIGH. Under these conditions the contents of the memory location specified on the address pins will appear on the four data I/O pins.

A die coat is used to ensure alpha immunity.



Selection Guide

	7C194-12 7C195-12 7C196-12	7C194-15 7C195-15 7C196-15	7C194-20 7C195-20 7C196-20	7C194-25 7C195-25 7C196-25	7C194-35 7C195-35 7C196-35	7C194-45 7C196-45
Maximum Access Time (ns)	12	15	20	25	35	45
Maximum Operating Current (mA)	155	145	135	115	115	
Maximum Standby Current (mA)	30	30	30	30	30	30

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Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage to Ground Potential0.5V to +7.0V
DC Voltage Applied to Outputs in High Z State $^{[1]}$ 0.5V to V_{CC} + 0.5V
DC Input Voltage ^[1] 0.5V to V_{CC} + 0.5V

Electrical Characteristics Over the Operating Range

Output Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	>2001V
	000 1

Latch-Up Current...... >200 mA

Operating Range

Range	Ambient Temperature ^[2]	v _{cc}
Commercial	0°C to +70°C	$5V \pm 10\%$

			7C194-12 7C195-12 7C196-12		7C1	94-15 95-15 96-15	
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = -4.0 mA	2.4		2.4		V
V _{OL}	Output LOW Voltage	V _{CC} = Min., I _{OL} = 8.0 mA		0.4		0.4	V
V _{IH}	Input HIGH Voltage		2.2	V _{CC} + 0.3V	2.2	V _{CC} + 0.3V	V
V _{IL} ^[1]	Input LOW Voltage		-0.5	0.8	-0.5	0.8	V
I _{IX}	Input Load Current	$GND \le V_I \le V_{CC}$	-5	+5	-5	+5	μΑ
I _{OZ}	Output Leakage Current	$GND \leq V_O \leq V_{CC},$ Output Disabled	-5	+5	-5	+5	μA
I _{OS}	Output Short Circuit Current ^[3]	V _{CC} = Max., V _{OUT} = GND		-300		-300	mA
I _{CC}	V _{CC} Operating Supply Current	V _{CC} =Max., I _{OUT} =0 mA, f=f _{MAX} =1/t _{RC}		155		145	mA
I _{SB1}	Automatic CE Power-Down Current —TTL Inputs ^[4]	$\begin{array}{l} \text{Max. } V_{CC}, \overline{CE}_{1,2} \geq V_{IH}, \\ V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, f = f_{MAX} \end{array}$		30		30	mA
I _{SB2}	Automatic CE Power-Down Current —CMOS Inputs ^[4]	$\begin{array}{l} \text{Max. } V_{\text{CC}}, \overline{\text{CE}}_{1,2} \geq V_{\text{CC}} \text{ - } 0.3V, \\ V_{\text{IN}} \geq V_{\text{CC}} \text{ - } 0.3V \text{ or} \\ V_{\text{IN}} \leq 0.3V, \text{ f} = 0 \end{array}$		10		10	mA

Notes:

Minimum voltage is equal to –2.0V for pulse durations of less than 20 ns. $T_{\rm A}$ is the "Instant On" case temperature. 1. 2.

3. 4.

Not more than 1 output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds. A pull-up resistor to V_{CC} on the CE input is required to keep the device deselected during V_{CC} power-up, otherwise I_{SB} will exceed values given.



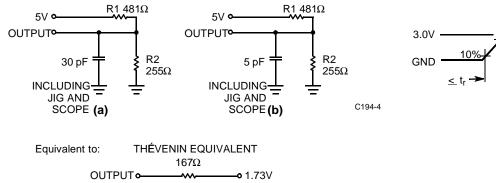
Electrical Characteristics Over the Operating Range (continued)

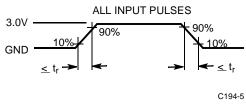
			7C194-20 7C195-20 7C196-20		7C194-25, 35, 45 7C195-25, 35 7C196-25, 35, 45		
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = -4.0 mA	2.4		2.4		V
V _{OL}	Output LOW Voltage	V _{CC} = Min., I _{OL} = 8.0 mA		0.4		0.4	V
V _{IH}	Input HIGH Voltage		2.2	V _{CC} + 0.3V	2.2	V _{CC} +0.3V	V
V _{IL}	Input LOW Voltage		-0.5	0.8	-0.5	0.8	V
I _{IX}	Input Load Current	$GND \leq V_I \leq V_{CC}$	-5	+5	-5	+5	μΑ
I _{OZ}	Output Leakage Current	$GND \leq V_O \leq V_{CC},$ Output Disabled	-5	+5	-5	+5	μA
I _{OS}	Output Short Circuit Current ^[3]	V _{CC} = Max., V _{OUT} = GND		-300		-300	mA
I _{CC}	V _{CC} Operating Supply Current	V _{CC} =Max., I _{OUT} =0 mA, f=f _{MAX} =1/t _{RC}		135		115	mA
I _{SB1}	Automatic CE Power-Down Current —TTL Inputs ^[4]	$\begin{array}{l} \text{Max. } V_{\text{CC}}, \overline{\text{CE}}_{1,2} \geq V_{\text{IH}}, \\ V_{\text{IN}} \geq V_{\text{IH}} \text{ or } \\ V_{\text{IN}} \leq V_{\text{IL}}, f = f_{\text{MAX}} \end{array}$		30		30	mA
I _{SB2}	Automatic CE Power-Down Current —CMOS Inputs ^[4]	$\begin{array}{l} \text{Max. } V_{CC}, \overline{CE}_{1,2} \geq V_{CC} - 0.3V, \\ V_{\text{IN}} \geq V_{CC} - 0.3V \text{ or} \\ V_{\text{IN}} \leq 0.3V, \text{ f} = 0 \end{array}$		15		15	mA

Capacitance^[5]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	8	pF
C _{OUT}	Output Capacitance	$V_{CC} = 5.0V$	10	pF

AC Test Loads and Waveforms^[6]





Notes:

5. Tested initially and after any design or process changes that may affect these parameters. 6. $t_r = \le 3$ ns for the -12 and -15 speeds. $T_{-r} = \le 5$ ns for the -20 and slower speeds.



Switching Characteristics Over the Operating Range^[7]

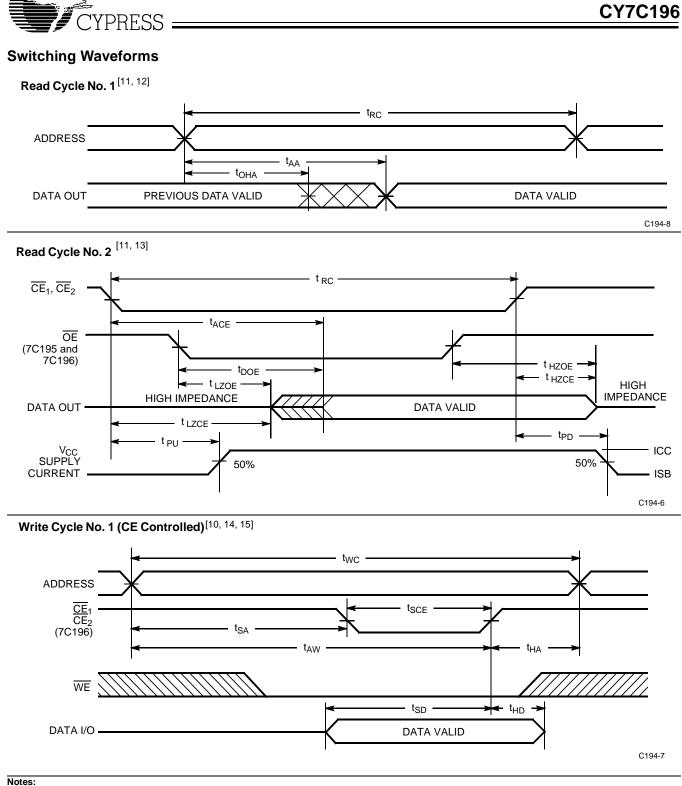
			7C1	94-12 95-12 96-12	7C19	94-15 95-15 96-15	7C19	94-20 95-20 96-20	7C1	94-25 95-25 96-25	7C1	94-35 95-35 96-35		94-45 96-45	
Parameter	arameter Description		Min.	Max.	Min.	Max.	Unit								
READ CYC	LE														
t _{RC}	Read Cycle	Time	12		15		20		25		35		45		ns
t _{AA}	Address to D Valid	ata		12		15		20		25		35		45	ns
t _{OHA}	Output Hold Address Cha		3		3		3		3		3		3		ns
t _{ACE1} , t _{ACE2}	CE LOW to Data Valid			12		15		20		25		35		45	ns
t _{DOE}	OE LOW to Data Valid	7C195, 7C196		5		7		9		10		16		16	ns
t _{LZOE}	OE LOW to Low Z	7C195, 7C196	0		0		0		3		3		3		ns
t _{HZOE}	OE HIGH to High Z ^[8]	7C195, 7C196		5		7		9		11		15		15	ns
t _{LZCE1} , t _{LZCE2}	CE LOW to Low Z ^[8]		3		3		3		3		3		3		ns
t _{HZCE1} , t _{HZCE2}	CE HIGH to High Z ^[8,8]			5		7		9		11		15		15	ns
t _{PU}	CE LOW to Power-Up		0		0		0		0		0		0		ns
t _{PD}	CE HIGH to Power-Down			12		15		20		25		35		45	ns
WRITE CYC	CLE ^[10]														
t _{WC}	Write Cycle	Гime	12		15		20		25		35		45		ns
t _{SCE}	CE LOW to V	Vrite End	9		10		15		18		22		22		ns
t _{AW}	Address Set- Write End	Up to	9		10		15		20		25		35		ns
t _{HA}	Address Hold Write End	d from	0		0		0		0		0		0		ns
t _{SA}	Address Set- Write Start	Up to	0		0		0		0		0		0		ns
t _{PWE}	WE Pulse W	idth	8		9		15		18		22		22		ns
t _{SD}	Data Set-Up to Write End		8		9		10		10		15		15		ns
t _{HD}	Data Hold from Write End		0		0		0		0		0		0		ns
t _{LZWE}	WE HIGH to Low Z ^[8]		3		3		3		3		3		3		ns
t _{HZWE}	WE LOW to High Z ^[8, 9]			7		7		10	0	13	0	15	0	20	ns

Notes:

7.

8. 9.

Test conditions assume signal transition time of 3 ns or less for -12 and -15 speeds and 5 ns or less for -20 and slower speeds, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance. t_{HZCE} , t_{HZCE} , and t_{HZWE} are specified with $C_L = 5$ pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage. At any given temperature and voltage condition, t_{HZCE} is less than t_{HZWE} is less than t_{HZWE} for any given device. The internal write time of the memory is defined by the overlap of CE_1 LOW, CE_2 LOW, and WE LOW. All signals must be LOW to initiate a write and any signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write. 10.



- 11. WE is HIGH for read cycle.

 12. Device is continuously selected: $\overline{CE}_1 = V_{II.}$, $\overline{CE}_2 = V_{II.}$ (7C196), and $\overline{OE} = V_{IL}$ (7C195 and 7C196).

 13. Address valid prior to or coincident with \overline{CE}_1 and \overline{CE}_2 transition LOW.

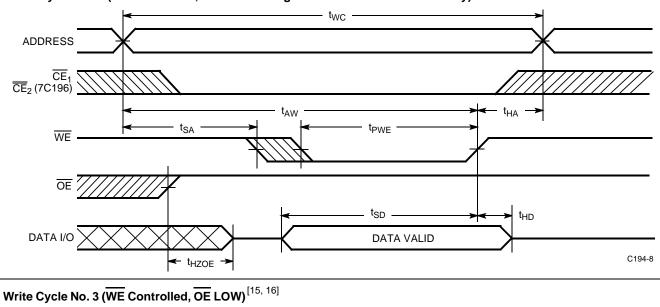
 14. Data I/O will be high impedance if $\overline{OE} = V_{IH}$ (7C195 and 7C196).

 15. If any \overline{CE} goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.

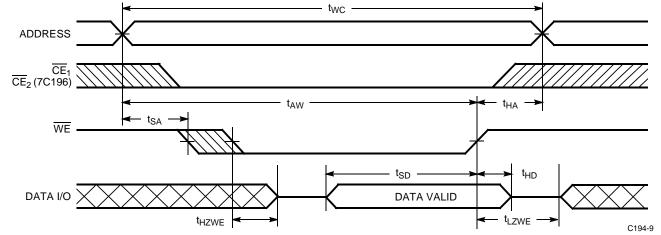
CY7C194 CY7C195



Switching Waveforms (continued)



Write Cycle No. 2 (WE Controlled, \overline{OE} HIGH During Write for 7C195 and 7C196 only)^[10, 14, 15]

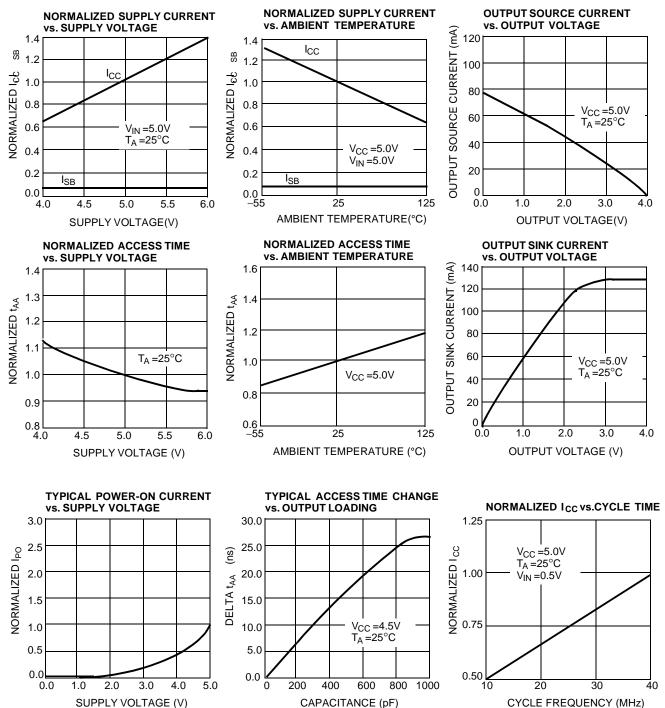


Note:

16. The minimum write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.



Typical DC and AC Characteristics





7C194 Truth Table

CE	WE	Data I/O	Mode	Power	
Н	X High Z		Deselect/Power-Down	Standby (I _{SB})	
L	Н	Data Out	Read	Active (I _{CC})	
L	L	Data In	Write	Active (I _{CC})	

7C195 Truth Table

CE ₁	WE	OE	E Data I/O Mode		Power
Н	Х	Х	High Z	Deselect/Power-Down	Standby (I _{SB})
L	Н	L	Data Out	Read	Active (I _{CC})
L	L	Х	Data In	Write	Active (I _{CC})
L	Н	Н	High Z	Deselect	Active (I _{CC})

7C196 Truth Table

CE1	CE ₂	WE	OE	Data I/O	Mode	Power
Н	Х	Х	Х	High Z	Deselect/Power-Down	Standby (I _{SB})
Х	Н	Х	Х			
L	L	Н	L	Data Out	Read	Active (I _{CC})
L	L	L	Х	Data In	Write	Active (I _{CC})
L	L	Н	Н	High Z	Deselect	Active (I _{CC})



Ordering Information

Speed (ns)	Speed (ns) Ordering Code		Package Type	Operating Range
12	CY7C194-12PC	CY7C194-12PC P13 24-Lead (300-Mil) Molded DIF		Commercial
	CY7C194-12VC	V13	24-Lead Molded SOJ	
15	CY7C194-15PC	P13	24-Lead (300-Mil) Molded DIP	Commercial
	CY7C194-15VC	V13	24-Lead Molded SOJ	
20	CY7C194-20PC	P13	24-Lead (300-Mil) Molded DIP	Commercial
	CY7C194-20VC	V13	24-Lead Molded SOJ	
25	CY7C194-25PC	P13	24-Lead (300-Mil) Molded DIP	Commercial
	CY7C194-25VC	V13	24-Lead Molded SOJ	
35	CY7C194-35PC	P13	24-Lead (300-Mil) Molded DIP	Commercial
	CY7C194-35VC	V13	24-Lead Molded SOJ	
45	CY7C194-45PC	P13	24-Lead (300-Mil) Molded DIP	Commercial
	CY7C194-45VC	V13	24-Lead Molded SOJ	

Speed (ns)	eed (ns) Ordering Code Pac		Package Type	Operating Range	
12	CY7C195-12PC	P21	28-Lead (300-Mil) Molded DIP	P Commercial	
	CY7C195-12VC	V21	28-Lead Molded SOJ		
15	CY7C195-15PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C195-15VC	V21	28-Lead Molded SOJ		
20	CY7C195-20PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C195-20VC	V21	28-Lead Molded SOJ		
25	CY7C195-25PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C195-25VC	V21	28-Lead Molded SOJ		
35	CY7C195-35PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C195-35VC	V21	28-Lead Molded SOJ		
45	CY7C195-45PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C195-45VC	V21	28-Lead Molded SOJ		

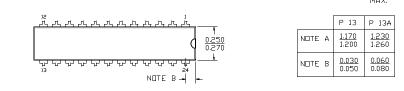
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range	
12	CY7C196-12PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C196-12VC	V21	28-Lead Molded SOJ		
15	CY7C196-15PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C196-15VC	V21	28-Lead Molded SOJ		
20	CY7C196-20PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C196-20VC	V21	28-Lead Molded SOJ		
25	CY7C196-25PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C196-25VC	V21	28-Lead Molded SOJ		
35	CY7C196-35PC	P21	28-Lead (300-Mil) Molded DIP	Commercial	
	CY7C196-35VC	V21	28-Lead Molded SOJ		

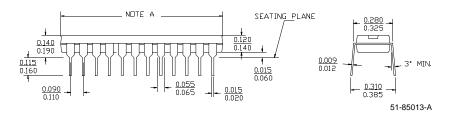


Package Diagrams

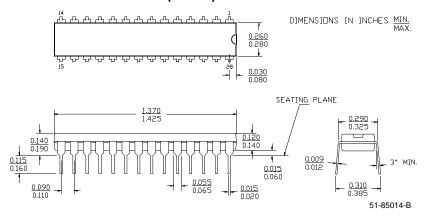
24-Lead (300-Mil) Molded DIP P13/P13A

DIMENSIONS IN INCHES MIN. MAX.



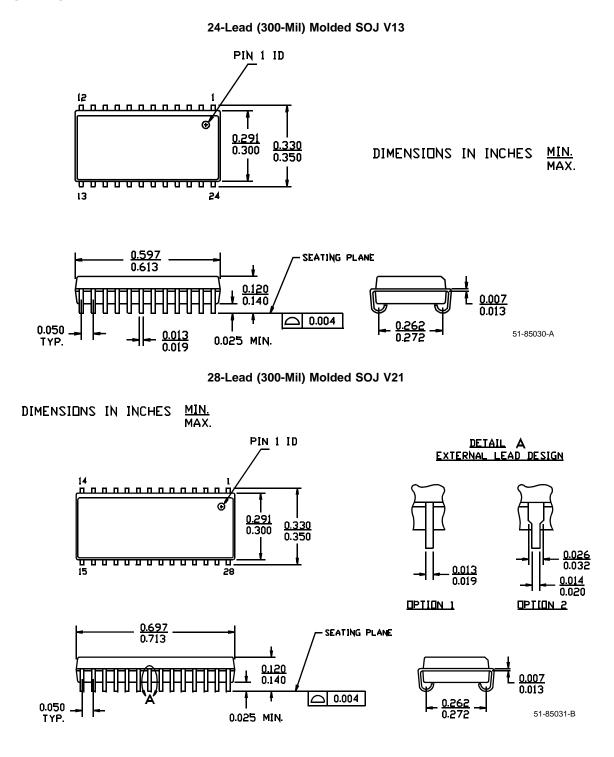


28-Lead (300-Mil) Molded DIP P21



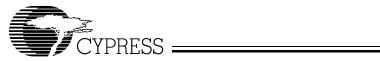


Package Diagrams (continued)



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